


<b>Search Notes</b>  	<b>Application/Control No.</b>  10594928	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Tan Ho	<b>Art Unit</b>  2821

SEARCHED			
Class	Subclass	Date	Examiner
343	702, 895, 901, 893	4/24/2008	TH

SEARCH NOTES		
Search Notes	Date	Examiner
None		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
343	702, 893	4/24/2008	TH